

APPLICATION DATA SHEET

09/914044
JC03 Rec'd PCT/TCO 22 AUG 2001

INVENTOR INFORMATION

Inventor one given name:: Shinchiro
Family name:: YAGI
Postal address line one:: c/o Shin-Etsu Handotai Co., Ltd.
Postal address line two:: Isobe R&D Center
Postal address line three:: 13-1, Isobe 2-chome, Annaka-shi
City:: Gunma
Country:: Japan
Postal or Zip Code:: 379-0196
City of residence:: Gunma
Country of residence:: Japan
Citizenship Country:: Japan

CORRESPONDENCE INFORMATION

Correspondence customer number:: 23911

APPLICATION INFORMATION

Title line one:: INSPECTION OBJECT SILICON WAFER
Title line two:: FOR THE PURPOSE OF DETECTING
Title line three:: CRYSTAL DEFECTS AND THE METHOD
Title line four:: OF DETECTION THEREOF
Total drawing sheets:: 1
Formal drawings?:: Yes
Application type:: utility
Docket Number:: 155/50324

REPRESENTATIVE INFORMATION

Representative customer number:: 23911

CONTINUITY INFORMATION

This application is a:: 371 of
Application one:: PCT/JP00/09135
Filing date:: 22 Dec 2000

PRIOR FOREIGN APPLICATIONS

Foreign application one:: 11-365947
Filing date:: 24 Dec 1999
Country:: Japan
Priority claimed:: Yes